



## Syllabus specific to Ultrasonic Testing of Welds using Time of Flight Diffraction

### 1. Level 1 Specific Theory

- 1.1 Background to the importance of the TOFD Technique
- 1.2 History of TOFD development
- 1.3 Principles of TOFD
- 1.4 Diffraction process
- 1.5 Basic TOFD set-up
- 1.6 Types of TOFD scan
- 1.7 Summary of advantages and disadvantages of TOFD, including limitations
- 1.8 Basic hardware
- 1.9 Advantage of digital recording
- 1.10 Digitisation of the analogue ultrasonic signals
- 1.11 Amplitude
- 1.12 Sampling rate
- 1.13 Selection of frequencies for filtering
- 1.14 Amount of data collected during an inspection
- 1.15 Grey scale imaging and B-scans
- 1.16 Signal averaging
- 1.17 Pulse width control
- 1.18 Software
- 1.19 On-line
- 1.20 Analysis and off-line facilities
- 1.21 Precision and resolution
- 1.22 Beam spread considerations
- 1.23 Basics for calculation of beam spread
- 1.24 Example of selection of number of scans for an inspection
- 1.25 Choice of probe angle
- 1.26 Transducer size and frequency
- 1.27 Choice of probe centre separation
- 1.28 Calibration of setting of gain
- 1.29 Digitisation rate
- 1.30 Signal averaging and pulse width
- 1.31 No signals – common faults
- 1.32 Manual versus mechanical scanning
- 1.33 General
- 1.34 Manual scanning
- 1.35 Mechanical scanning
- 1.36 Sampling interval
- 1.37 Summary of choice of parameters for TOFD Scan
- 1.38 Introduction
- 1.39 Timing errors
- 1.40 Near surface problems
- 1.41 Off-axis error and back wall blind zone
- 1.42 Off-axis depth error
- 1.43 Back wall blind zone
- 1.44 Errors in couplant thickness, surface height variations and velocity
- 1.45 Large grained materials
- 1.46 Overall errors and monitoring growth
- 1.47 Overall errors



- 1.48 Monitoring defect growth
- 1.49 Data assessment – flaw characterisation
- 1.50 Shear waves
- 1.51 Pores and slugs in TOFD records
- 1.52 Internal cracks
- 1.53 Upper surface breaking cracks
- 1.54 Lower surface breaking cracks
- 1.55 Effect of changing defect profile
- 1.56 Weld root flaws
- 1.57 Check transparency
- 1.58 Transverse flaws
- 1.59 Analysis software
- 1.60 Linearisation
- 1.61 Lateral/back wall straighten and removal
- 1.62 Parabolic cursor
- 1.63 Synthetic aperture focusing technique (SAFT)
- 1.64 Split spectrum processing
- 1.65 Curved surface
- 1.66 Complex geometry



## 2. Level 2 Specific Theory

As Level 1 but in addition:

- 2.1 Flaw sizing with the pulse echo technique
- 2.2 Comparison of flaw sizing accuracy for different techniques
- 2.3 Angular variation of diffraction signals
- 2.4 Effect of change in probe separation and importance of calibration with lateral and back wall signals
- 2.5 Change in probe separation
- 2.6 Importance of calibration
- 2.7 Error due to variations in couplant depth
- 2.8 Error due to variations in surface profile
- 2.9 Velocity error
- 2.10 Index point migration errors
- 2.11 Other errors
- 2.12 Multiple arcs
- 2.13 Procedure writing
- 2.14 Equipment and probe checks
- 2.15 Equipment checks
- 2.16 Screen height linearity
- 2.17 Amplitude linearity
- 2.18 Time base linearity
- 2.19 Probe index emission point
- 2.20 Beam angle
- 2.21 Beam spread
- 2.22 TOFD combined probe delay
- 2.23 Sensitivity
- 2.24 Resolution
- 2.25 Probe checks
- 2.26 Material velocity measurement
- 2.27 Probe frequency
- 2.28 Probe pulse length